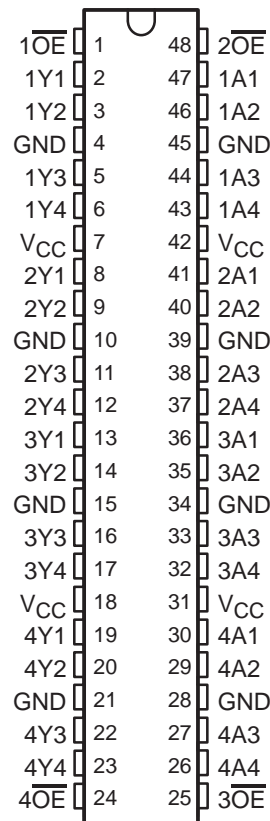


SN54ABTH16244, SN74ABTH16244 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

SCBS677D – SEPTEMBER 1996 – REVISED MARCH 2000

- Members of the Texas Instruments *Widebus™* Family
- State-of-the-Art *EPIC-II B™* BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- Typical V_{OLP} (Output Ground Bounce) <1 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$
- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs ($-32\text{-mA } I_{OH}$, $64\text{-mA } I_{OL}$)
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model ($C = 200$ pF, $R = 0$)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), Thin Very Small-Outline (DGV) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages

SN54ABTH16244 . . . WD PACKAGE
SN74ABTH16244 . . . DGG, DGV, OR DL PACKAGE
(TOP VIEW)



description

The 'ABTH16244 devices are 16-bit buffers and line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and symmetrical active-low output-enable (\overline{OE}) inputs.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN54ABTH16244 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABTH16244 is characterized for operation from -40°C to 85°C .



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

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On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

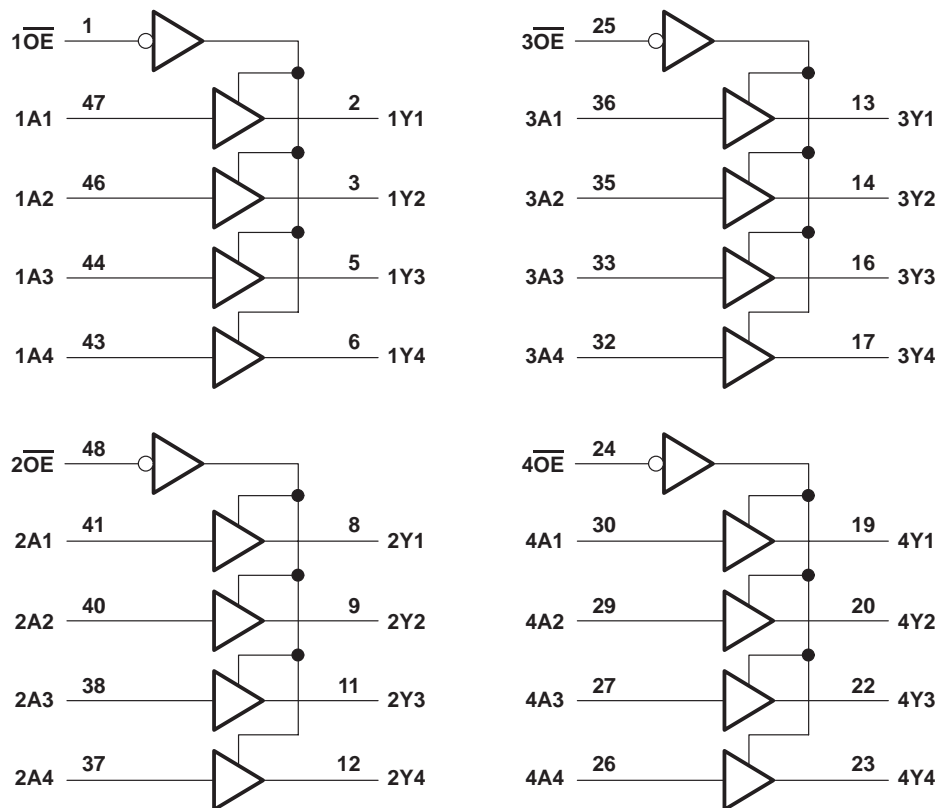
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INPUTS		OUTPUT Y
OE	A	
L	H	H
L	L	L
H	X	Z

$\overline{1OE}$	1		EN1		
$\overline{2OE}$	48		EN2		
$\overline{3OE}$	25		EN3		
$\overline{4OE}$	24		EN4		
1A1	47	1	1	▽	2 1Y1
1A2	46				3 1Y2
1A3	44				5 1Y3
1A4	43				6 1Y4
2A1	41	1	2	▽	8 2Y1
2A2	40				9 2Y2
2A3	38				11 2Y3
2A4	37				12 2Y4
3A1	36	1	3	▽	13 3Y1
3A2	35				14 3Y2
3A3	33				16 3Y3
3A4	32				17 3Y4
4A1	30	1	4	▽	19 4Y1
4A2	29				20 4Y2
4A3	27				22 4Y3
4A4	26				23 4Y4

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input voltage range, V_I (see Note 1)	–0.5 V to 7 V
Voltage range applied to any output in the high or power-off state, V_O	–0.5 V to 5.5 V
Current into any output in the low state, I_O : SN54ABTH16244	96 mA
SN74ABTH16244	128 mA
Input clamp current, I_{IK} ($V_I < 0$)	–18 mA
Output clamp current, I_{OK} ($V_O < 0$)	–50 mA
Package thermal impedance, θ_{JA} (see Note 2): DGG package	70°C/W
DGV package	58°C/W
DL package	63°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

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16-BIT BUFFERS/DRIVERS

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recommended operating conditions (see Note 3)

			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage		4.5	5.5	4.5	5.5	V
V _{IH}	High-level input voltage		2		2		V
V _{IL}	Low-level input voltage			0.8		0.8	V
V _I	Input voltage		0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current			–24		–32	mA
I _{OL}	Low-level output current			48		64	mA
Δt/Δv	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
T _A	Operating free-air temperature		–55	125	–40	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T _A = 25°C			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	TYP†	MAX	MIN	MAX	MIN	MAX	
V _{IK}	V _{CC} = 4.5 V,	I _I = –18 mA			–1.2		–1.2		–1.2	V
V _{OH}	V _{CC} = 4.5 V,	I _{OH} = –3 mA	2.5			2.5		2.5		V
	V _{CC} = 5 V,	I _{OH} = –3 mA	3			3		3		
	V _{CC} = 4.5 V	I _{OH} = –24 mA	2			2				
		I _{OH} = –32 mA	2*					2		
V _{OL}	V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			V
		I _{OL} = 64 mA			0.55*				0.55	
V _{hys}				100						mV
I _I	V _{CC} = 5.5 V,	V _I = V _{CC} or GND			±1		±1		±1	μA
I _I (hold)	V _{CC} = 4.5 V	V _I = 0.8 V	100			100		100		μA
		V _I = 2 V	–40			–40		–40		
I _{OZH}	V _{CC} = 5.5 V,	V _O = 2.7 V			10		10		10	μA
I _{OZL}	V _{CC} = 5.5 V,	V _O = 0.5 V			–10		–10		–10	μA
I _{off}	V _{CC} = 0,	V _I or V _O ≤ 4.5 V			±100				±100	μA
I _{CEX}	V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50		50		50	μA
I _O ‡	V _{CC} = 5.5 V,	V _O = 2.5 V	–50	–100	–180	–50	–180	–50	–180	mA
I _{CC}	V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND	Outputs high			3		3		3	mA
		Outputs low			32		32		32	
		Outputs disabled			3		3		3	
ΔI _{CC} §	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND				1.5		1.5		1.5	mA
C _i	V _I = 2.5 V or 0.5 V				3					pF
C _o	V _O = 2.5 V or 0.5 V				8					pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.

† All typical values are at V_{CC} = 5 V.

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

§ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$			SN54ABTH16244		SN74ABTH16244		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	1	2.3	3.2	0.7	3.6	1	3.5	ns
t_{PHL}			1	2.6	3.7	0.5	4.2	1	4.1	
t_{PZH}	\overline{OE}	Y	1	3	3.8	0.7	4.9	1	4.8	ns
t_{PZL}			1	3.2	4	0.9	5.3	1	4.8	
t_{PHZ}	\overline{OE}	Y	1	3.6	4.4	0.7	5.3	1	4.8	ns
t_{PLZ}			1	2.9	3.7	1	4.6	1	4.1	

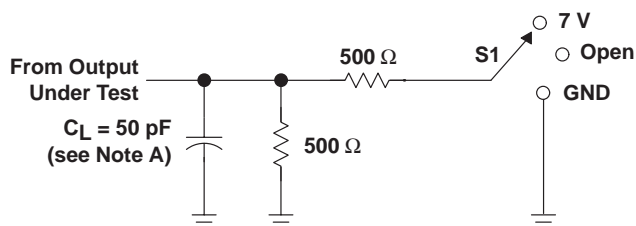
SN54ABTH16244, SN74ABTH16244

16-BIT BUFFERS/DRIVERS

WITH 3-STATE OUTPUTS

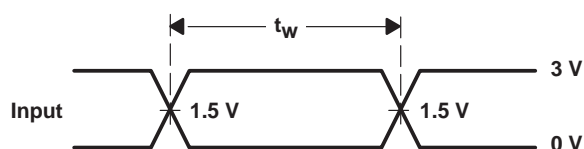
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PARAMETER MEASUREMENT INFORMATION

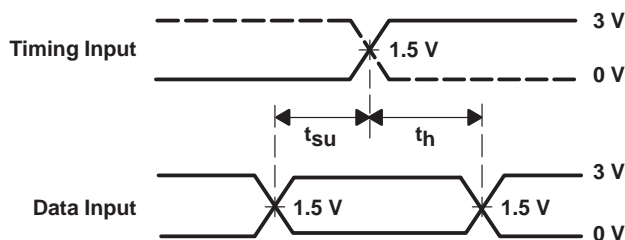


LOAD CIRCUIT

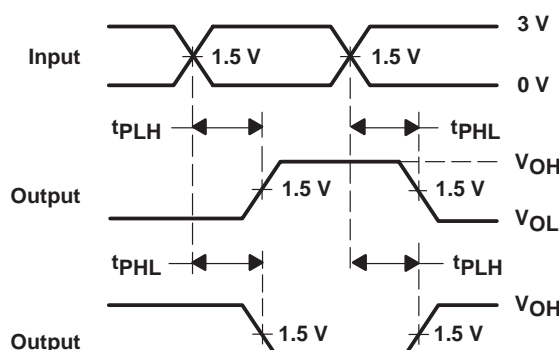
TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open



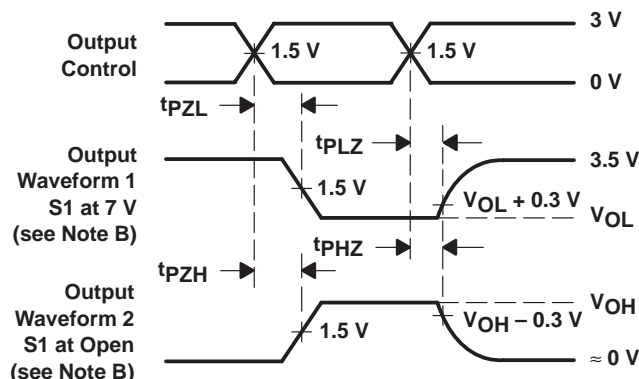
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r \leq 2.5 \text{ ns}$, $t_f \leq 2.5 \text{ ns}$.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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